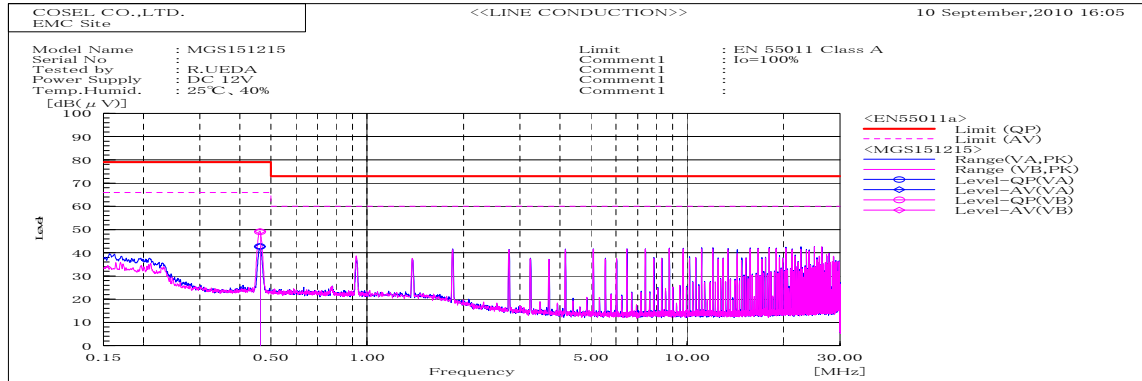
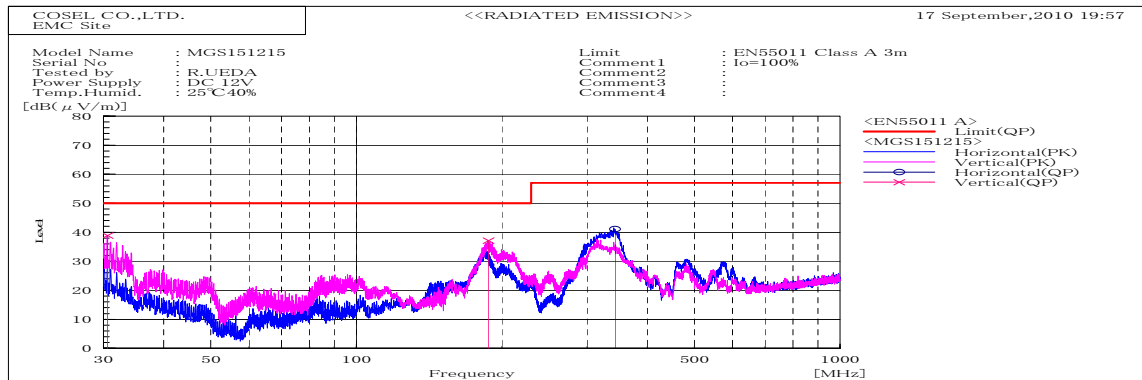


DATA SHEET

Model	MGS151215	Date	21-Sep-10
Test	EMI	Temp.	25 degreeC
	Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46311		VB	39	39.2	10	49	49.2	79	66	30	16.8	Pass	
0.46256		VA	32.6	32.5	10.1	42.7	42.6	79	66	36.3	23.4	Pass	

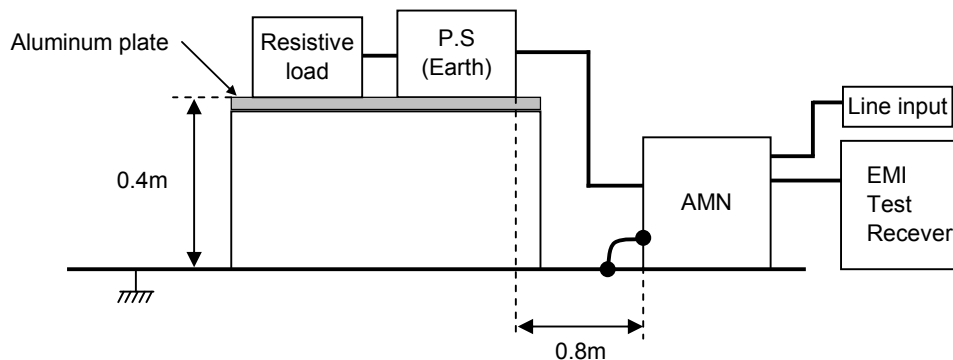


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
30.566	V	Stable	52.6	-13.7		38.9		50	11.1	Pass	109	295	
187.521	V	Stable	59.2	-22.1		37.1		50	12.9	Pass	152	262	
342.441	H	Stable	57.6	-16.5		41.1		57	15.9	Pass	104	169	

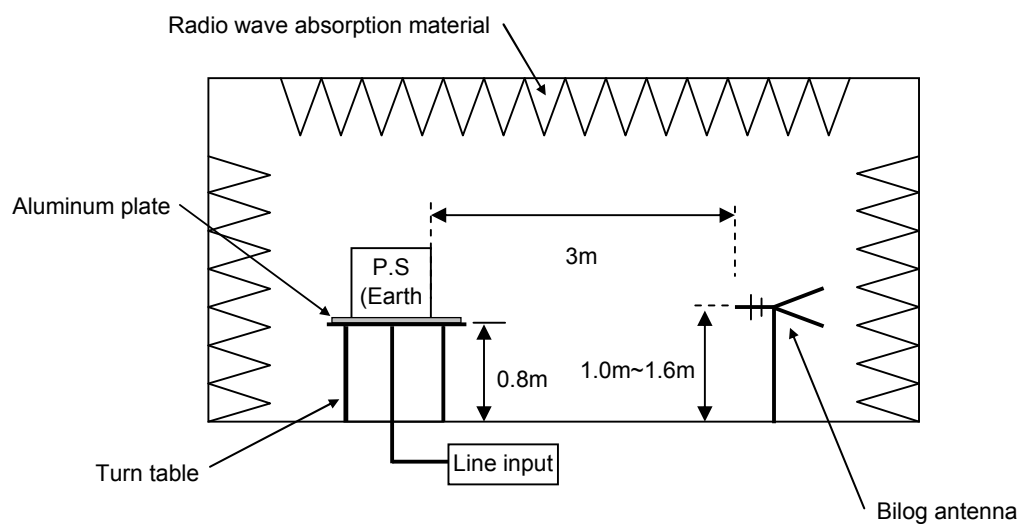
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



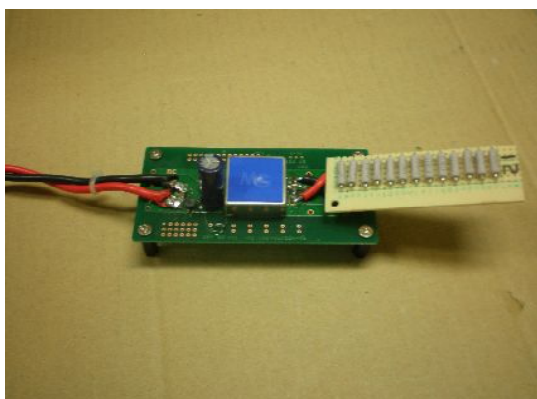


Conditions

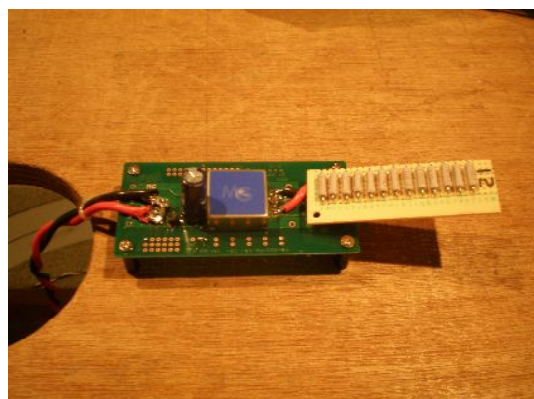
Test : EMI
Model Name : MGS1512□□/MGW1512□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

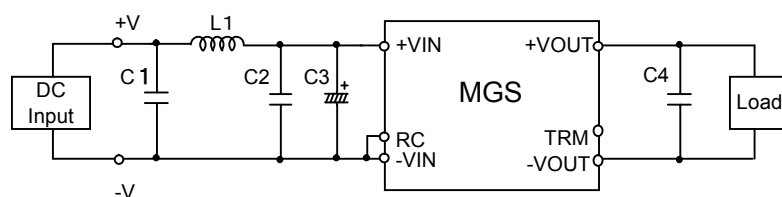


Fig.1 Testing circuitry 1

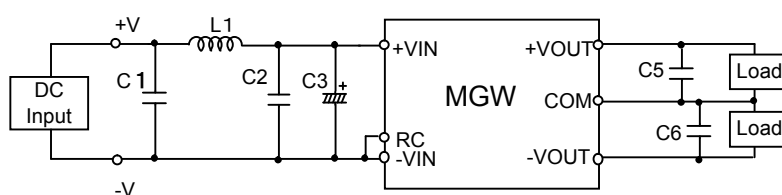


Fig.2 Testing circuitry 2

L1	: 0.5 μ H	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	: 25V 10 μ F	CM316X5R106K25A	(KYOCERA)
C3	: 50V 220 μ F	LXY50VB220M	(NIPPON CHEMI-CON)
C4,C5,C6	: 25V 22 μ F	CM32X5R226K25A	(KYOCERA)